Registration fees

<table>
<thead>
<tr>
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<th>Until June 1st, 2011</th>
<th>After June 1st, 2011</th>
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</thead>
<tbody>
<tr>
<td>Student</td>
<td>400 €</td>
<td>500 €</td>
</tr>
<tr>
<td>Academic people</td>
<td>750 €</td>
<td>900 €</td>
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<tr>
<td>Industrial people</td>
<td>750 €</td>
<td>900 €</td>
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</tbody>
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Add 19.6% (VAT) for EC citizen

In order to ensure and encourage individual interaction the number of participants will be limited to 40.

Registration fees include:
- Admission and participation to the course
- Coffee breaks, lunches, reception and two conferences dinner

Participants will be required to make their own accommodation and travelling arrangements to and from workshop venue. Organizers will send an hotels list and an access map of the training place. Upon request organizers can make accommodation bookings for participants.

Please direct questions or registration to INEL:

info@inel.fr
Tel 33(0)2 38 80 45 45
Fax 33(0)2 38 80 08 14

General information

Venue
The workshop will be held at Caen, France.
IUT, UCBN, CRISMAT ENSICAEN

Access
Caen is located in Normandy at 250 km west of Paris. Further more details are available in the registration form.

Organizers

INEL SAS
Z.A. - C.D. 405
45410 Artenay
France
Phone: +33(0)2 38 80 45 45
Fax: + 33(0)2 38 80 08 14
http://www.inel.fr
Email: info@inel.fr

X-ray diffraction for the 21st Century

WORKSHOP
Combined Analysis Using X-ray and Neutron Scattering
July 4–8, 2011
Caen (France)
Aim of the workshop

Is to allow students, academic and non-academic researchers to obtain information relating to the characterisation, structure, microstructure, phase, texture, stress and reflectivity by "Combined Analysis using X-ray and neutron scattering techniques" and relating to a number of samples and structures including: thin films, bulk materials, materials with anisotropic crystal structures, polyphased materials, nanomaterials, multi-detectors, etc.

Each type of analysis will be considered individually and then integrated into a combined analysis program. Some specific examples will be studied using X-ray and neutron experimental data.

The objective is to bring together participants from various fields and to provide an opportunity to discuss individual interests and experience.

X-ray equipment used at the CRISMAT laboratory and by INEL will be used to demonstrate technical aspects and to support the theoretical and practical issues of this course.

Topics

The workshop will cover many aspects of "Combined Analysis" by X-ray and neutron scattering, ranging from fundamental requirements to technically relevant industrial and academic applications.

- Diffraction technique, an overview
- Crystallography Texture Analysis
- Residual Stress Analysis
- Rietveld analysis
- Reflectivity analysis
- Phase analysis
- Phase and line broadening analysis
- The combined solution
- Using MAUD software

Pre-requisites

The necessary pre-requisites are as follows:

- Basic knowledge of crystallography and diffraction techniques
- Good practice in the use of computers
- If possible, bring your laptop for the practical sessions

Our Team of Speakers

Daniel Chateigner, Caen (France)
Luca Lutterotti, Trento (Italia)
Christophe Fontugne, Artenay (France)
Olivier Perez, Caen (France)
Magali Morales, Caen (France)

Registration

If you are interested in this workshop, please contact INEL by an email entitled "Inel Crismat workshop" to:

Email: info@inel.fr
Phone: +33(0)2 38 80 45 45

We will send you a registration form by email that you will have to fill out and send back to us. You will also receive the workshop program as well as the procedure to install the software on your PC before the start of the workshop. Payment conditions and tourism information will be included.

Registration Deadline
June 15th, 2011